

Notice of References Cited	Application/Control No. 10/026,709	Applicant(s)/Patent Under Reexamination TAKAHASHI ET AL.	
	Examiner Kevin M Bernatz	Art Unit 1773	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,851,582	12-1998	Tamari et al.	427/130
	B	US-2002/0150793	10-2002	Maeda et al.	428/694.0TM
	C	US-5,853,847	12-1998	Takahashi, Migaku	428/141
	D	US-2002/0001736	01-2002	Akimoto et al.	428/694.00T
	E	US-6,500,567	12-2002	Bertero et al.	428/667
	F	US-4,652,499	03-1987	Howard, James K.	428/641
	G	US-6,303,217	10-2001	Malhotra et al.	428/332
	H	US-6,255,006	07-2001	Ohnami et al.	428/694TS
	I	US-6,423,431	07-2002	Wong et al.	428/694TS
	J	US-6,537,686	03-2003	Chen, Ga-Lane	428/678
	K	US-6544667	04-2003	Hosoe et al.	428/664
	L	US-2002/0122960	09-2002	Hanawa et al.	428/694.0TS
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Djayaprawira et al. (IEEE Trans. Mag., 37(4), 2001, 1497 - 1499).
	V	Ikeda et al. (IEEE Trans. Mag., 33(5), 1997, 3079 - 3081).
	W	Hirayama et al. (J. App. Phys, 87(9), 2000, 6890 - 6892).
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.